

<b>Notice of References Cited</b>	Application/Control No. 10/661,147		Applicant(s)/Patent Under Reexamination SAED, ARYAN	
	Examiner Temesghen Ghebretinsae		Art Unit 2611	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0109508 A1	06-2004	Jeon et al.	375/260
*	B	US-2003/0210645 A1	11-2003	Gummadi et al.	370/203
*	C	US-6,567,480 B1	05-2003	Brardjanian et al.	375/331
*	D	US-2003/0128751 A1	07-2003	Vandenameele-Lepla, Patrick	375/229
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sliskovic "Carrier and Sampling frequency Offset Estimation and Correction in Multicarrier Systems" IEEE 2001
	V	Lei et al "Improved Joint Carrier and Sampling frequency Offset Estimation Scheme for OFDM Systems" Globecom, IEEE 2003
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.